PATENT ABSTRACTS OF JAPAN

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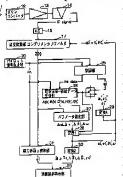
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(54) WAVEFORM QUALITY MEASURING METHOD FOR CDMA SIGNAL



(57)Abstract: PROBLEM TO BE SOLVED: To improve measurement precision.

SOLUTION: A measurement signal Z(k) of a base-band from an orthogonal conversion part 17 is demodulated by the PN code of a pilot signal in a demodulation part 25. The demodulation bit string and amplitude a'i is detected. An ideal signal Ri is generated from them and the PN code. Auxiliary data A, B, C, H and I for solving approximated simultaneous equations obtaining parameters for minimizing the square of the error of Ri and Z(k) are obtained (26). Then, the simultaneous equations are solvent from them and Z(k). Parameters Δai, Δτi, Δθi and Δω are estimated (27). Thus, Z(k), Ri, A, B, C, H and I are corrected by the finding of parameter estimation is repeated again until the parameter is optimized. Then, an electric coefficient of is obtained by Z(k) and PN.